CLEANING, IN-SITU

- Polish cleaning media if probing in-situ. These are the ITS part numbers based on prober type:
 - PP-2001-9903SCM, 2" 99% ITS P8/P8E
 PP-2010-9903SCM, 1.5"x1.5 ITS EG4085
 PP-2049-9903SC/I-M 4.25" P8XL-LC
- Tungsten Carbide also works well with Celadon probe cards.
- Celadon recommends a combination of these two cleaning methods.
 - Perform PP clean as often as every 250-500 devices.
 - Touch down on PP up to 30 times. Touch down in an array pattern to prevent from damaging the pad. Overdrive should be increased when probing probe polish, up to 100u has worked well.
 - To keep CRES in check, periodically touch down on tungsten carbide to remove embedded particles. Touch down on the tungsten carbide no more than 5 times on each cleaning cycle.

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